

# **650V GaN Power Transistor (FET)**

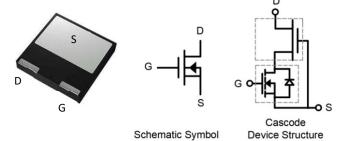
#### **Features**

- Easy to use, compatible with standard gate drivers
- Excellent Q<sub>G</sub> x R<sub>DS(on)</sub> figure of merit (FOM)
- Low Q<sub>RR</sub>, no free-wheeling diode required
- Low switching loss
- RoHS compliant and Halogen-free

Product Summary		
$V_{DSS}$	650	٧
R <sub>DS(on), typ</sub>	180	mΩ
Q <sub>G, typ</sub>	20	nC
Q <sub>RR, typ</sub>	26	nC

# **Applications**

- High efficiency power supplies
- Telecom and datacom
- Automotive
- Servo motors



# **Packaging**

Part Number	Package	Packaging	Base QTY
RX65T180HS2A	DFN 8 x 8	Tape and Reel	2500

## Maximum ratings, at T<sub>C</sub>=25 ℃, unless otherwise specified

Symbol	Parameter	Limit Value	Unit	
	Continuous drain current @T <sub>C</sub> =25℃	14	Α	
I <sub>D</sub>	Continuous drain current @T <sub>C</sub> =100℃		9	А
	Pulsed drain current @T <sub>C</sub> =25℃ (pulse	62	Α	
I <sub>DM</sub>	Pulsed drain current @T <sub>C</sub> =150℃ (pul	46	Α	
V <sub>DSS</sub>	Drain to source voltage (T₁ = -55℃ to 150℃)		650	V
V <sub>TDSS</sub>	Transient drain to source voltage <sup>a</sup>	800	V	
V <sub>GSS</sub>	Gate to source voltage		±20	V
P <sub>D</sub>	Maximum power dissipation @T <sub>c</sub> =25℃		62.5	W
T <sub>C</sub>	O	Case	-55 to 150	°C
T <sub>J</sub>	Operating temperature	Junction	-55 to 150	°C
Ts	Storage temperature	-55 to 150	°C	
T <sub>CSOLD</sub>	Soldering peak temperature		260	°C



#### **Thermal Resistance**

Symbol	Symbol Parameter		Unit
Rөлс	Rejic Junction-to-case		%/W
Rоја	Junction-to-ambient <sup>b</sup>	50	℃/W

#### Notes:

- a. Off-state spike duty cycle < 0.01, spike duration < 2us
- b. Device on one layer epoxy PCB for drain connection (vertical and without air stream cooling, with 6cm<sup>2</sup> copper area and 70μm thickness)



# Electrical Parameters, at $T_J$ =25 $^{\circ}$ C, unless otherwise specified

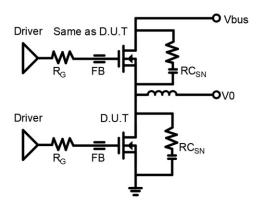
Symbol	Min	Тур	Max	Unit	Test Conditions	
Forward Chara	cteristics	1	I	1		
$V_{DSS\text{-MAX}}$	650	-	-	V	V <sub>GS</sub> =0V	
$BV_{DSS}$	-	1000	-	V	V <sub>GS</sub> =0V, I <sub>DSS</sub> =250μA	
$V_{GS(th)}$	3	4	5	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =500μA	
D C	-	180	225	mΩ	V <sub>GS</sub> =8V, I <sub>D</sub> =4A, T <sub>J</sub> =25℃	
$R_{DS(on)}$	-	360	-	11152	V <sub>GS</sub> =8V, I <sub>D</sub> =4A, T <sub>J</sub> =150℃	
1	-	10	22	μΑ	V <sub>DS</sub> =700V, V <sub>GS</sub> =0V, T <sub>J</sub> =25℃	
I <sub>DSS</sub>	-	55	-	μΑ	V <sub>DS</sub> =700V, V <sub>GS</sub> =0V, T <sub>J</sub> =150℃	
1	-	-	150	nA	V <sub>GS</sub> =20V	
I <sub>GSS</sub>	-	-	-150	nA	V <sub>GS</sub> =-20V	
C <sub>ISS</sub>	-	585	-	pF		
C <sub>OSS</sub>	-	25	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =650V, f=1MHz	
C <sub>RSS</sub>	-	1	-	pF		
C <sub>O(er)</sub>	-	34	-	pF	V 0V V 0 550V	
C <sub>O(tr)</sub>	-	78	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =0 - 650V	
$Q_{G}$	-	20	-			
$Q_{GS}$	-	6.7	-	nC	V <sub>DS</sub> =400V, V <sub>GS</sub> =0 - 12V, I <sub>D</sub> =10A	
$Q_{GD}$	-	4	-			
t <sub>D(on)</sub>	-	43	-			
t <sub>R</sub>	-	15	-		V 400V V 0 40V L 40A B 40O	
t <sub>D(off)</sub>	-	39	-	ns	$V_{DS}$ =400V, $V_{GS}$ =0 - 12V, $I_{D}$ =10A, $R_{G}$ =40 $\Omega$	
t <sub>F</sub>	-	11	-			
Reverse Chara	cteristics					
	-	1.3	-	V	V <sub>GS</sub> =0V, I <sub>S</sub> =5A, T <sub>J</sub> =25℃	
$V_{SD}$	-	1.9	-		V <sub>GS</sub> =0V, I <sub>S</sub> =10A, T <sub>J</sub> =25℃	
	-	3	-		V <sub>GS</sub> =0V, I <sub>S</sub> =10A, T <sub>J</sub> =150℃	
t <sub>RR</sub>	-	16	-	ns		
$Q_{RR}$	_	26	_	nC	$I_S=10A$ , $V_{GS}=0V$ , $d_i/d_t=1000A/us$ , $V_{DD}=400$	

#### Notes:

c. Dynamic on-resistance; see Figure 17 and 18 for test circuit and configurations



## **Circuit Implementation**



## **Recommended Single Ended Drive Circuit**

Recommended gate drive: (0 V, 12 V) with  $R_{G(tot)} = 34 \Omega$ , where  $R_{G(tot)} = R_G + R_{Driver}$ 

Gate Ferrite Bead	Gate Resistance1	RC Snubber
(FB)	(R <sub>G</sub> )	(RC <sub>SN</sub> )
MPZ1608S471ATA00	33 Ω	69 pF + 15 Ω

#### Notes:

- d. RCsn should be placed as close as possible to the drain pin
- e. The layout and wiring of the drive circuit should be as short as possible



## Typical Characteristics, at T<sub>c</sub>=25 ℃, unless otherwise specified

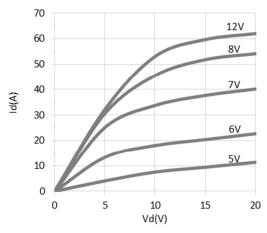


Figure 1. Typical Output Characteristics  $T_J$ =25°C

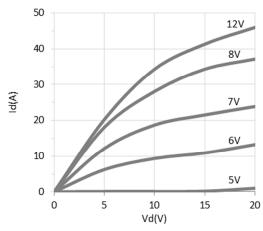


Figure 2. Typical Output Characteristics T₁=150°C

3.0

8

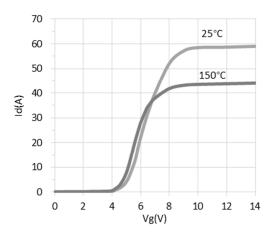
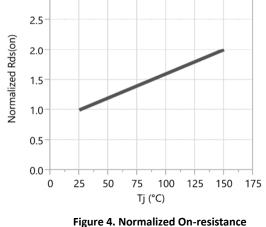


Figure 3. Typical Transfer Characteristics

V<sub>DS</sub>=10V, Parameter: T<sub>J</sub>



gure 4. Normalized On-resistance  $I_D=4A$ ,  $V_{GS}=12V$ 

1000 Ciss 100 Capacitance(pF) Coss 10 1 Crss 0.1 0 100 200 300 400 500 600 700 Vd(V)

Figure 5. Typical Capacitance

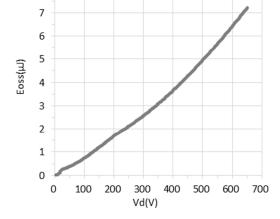
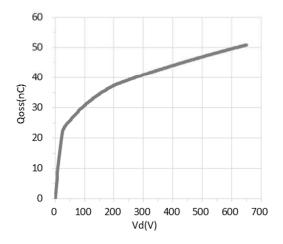


Figure 6. Typical Coss Stored Energy

V<sub>GS</sub>=0V, f=1MHZ



## Typical Characteristics, at T<sub>c</sub>=25 ℃, unless otherwise specified



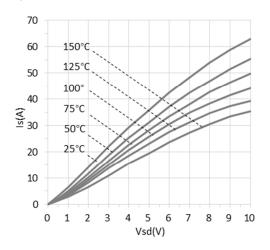
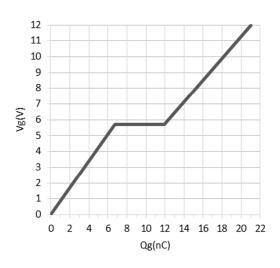


Figure 7. Typical Qoss

Figure 8. Forward Characteristic of Rev. Diode



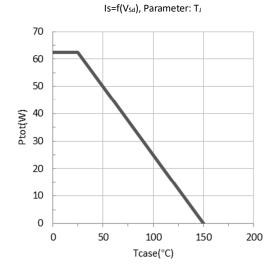
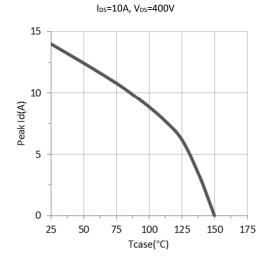


Figure 9. Typical Gate Charge

Figure 10. Power Dissipation



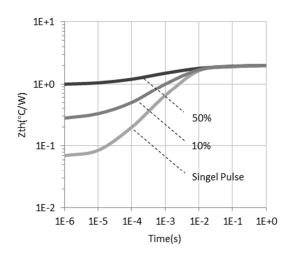


Figure 11. Current Derating

Figure 12. Transient Thermal Resistance



## Typical Characteristics, at $T_C$ =25 $^{\circ}$ C, unless otherwise specified

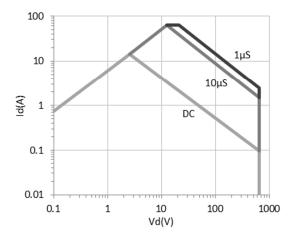


Figure 13. Safe operating Area T<sub>c</sub>=25 °C (calculated based on thermal limits)

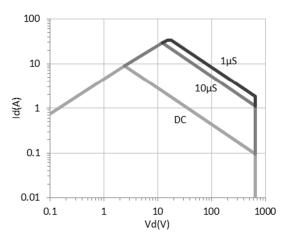


Figure 14. Safe operating Area T<sub>c</sub>=80 °C (calculated based on thermal limits)



#### **Test Circuits and Waveforms**

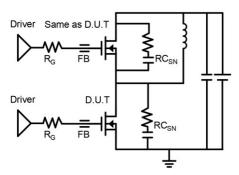


Figure 15. Switching Time Test Circuit

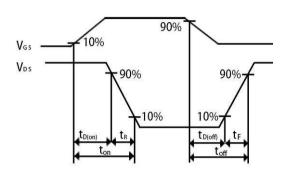


Figure 16. Switching Time Waveform

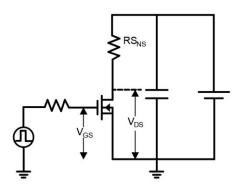


Figure 17. Dynamic  $R_{DS(on)}$  Test Circuit

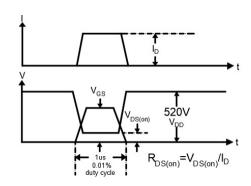


Figure 18. Dynamic  $R_{DS(on)}$  Waveform

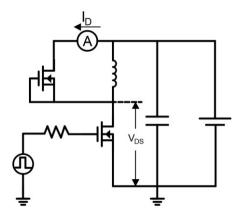


Figure 19. Diode Characteristic Test Circuit

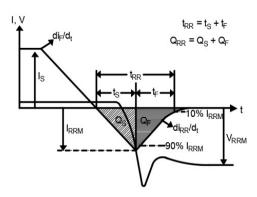


Figure 20. Diode Recovery Waveform



## **Design Considerations**

Fast switching GaN device can reduce power conversion losses, and thus enable high frequency operations. Certain PCB design rules and instructions, however, need to be followed to take full advantages of fast switching GaN devices.

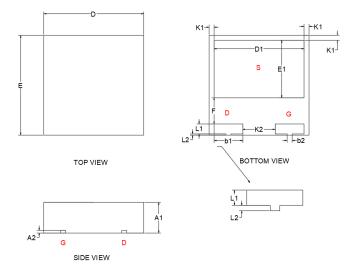
Before evaluating Runxin Micro's GaN devices, please refer to the table below which provides some practical rules that should be followed during the evaluation.

#### When Evaluating Runxin Micro's GaN Devices:

DO	DO NOT
Make sure the traces are as short as possible for both	Using Runxin Micro's devices in GDS board layouts
drive and power loops to minimize parasitic inductance	
Use the test tool with the shortest inductive loop, and	Use differential mode probe or probe ground clip with
make sure test points should be placed close enough	long wires
Minimize the lead length of TO packages when	Use long traces in drive circuit, or long lead length of
installing them to PCB	the devices



## **Package Outline**

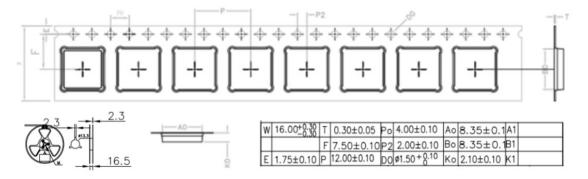


## DFN 8 x 8mm (HS) Package

Complete	Dimensions in Millimeters			
Symbol	MIN	NOM	MAX	
A1	0.850	0.900	0.950	
A2	0.195	0.203	0.211	
D	7.950	8.000	8.050	
E	7.950	8.000	8.050	
D1	7.150	7.200	7.250	
E1	4.550	4.600	4.650	
k1	0.375	0.400	0.425	
k2	2.575	2.600	2.625	
b1	2.275	2.300	2.325	
b2	0.375	0.400	0.425	
L1	0.775	0.800	0.825	
L2	0.075	0.100	0.125	
F	2.075	2.100	2.125	

## **Tape and Reel Information**

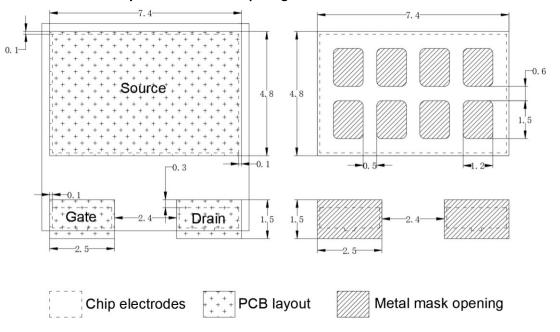
#### Dimensions are shown in millimeters





## **Recommended PCB Layout & Metal mask opening**

#### Dimensions are shown in millimeters



#### **Revision History**

Version	Date	Change(s)	
0.1	05/15/2023	Released preliminary datasheet	